•		ATTY DOCKET NO. 03500.015727.1	APPLICATION NO.	NYA			
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DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE		
6,624,589	9/03	Kitamura et al.	315	169.3			
6,628,053	9/03	Den et al.	313	310	·		
6,626,719	9/03	Ono et al.	445	24			
2002/0060516 A1	5/02	Kawate et al.	313	495			
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2002/0047513 A1	4/02	Nomura	313	495			
2003/0006684 A1	1/03	Kawate et al.	313	311			
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2003/0057860 A1	3/03	Tsukamoto	315	169.3			
6,087,765	7/00	Coll et al.	313	309			
5,872,422	2/16/99	Xu et al.	313	311			
2002/0009637	1/02	Murakami et al.	429	213			
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DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT		
WO 01/93292	12/01	PCT					
10-149760	6/98	JAPAN			ABSTRACT		
AMH 10-149760 6/98 JAPAN ABSTRACT  OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
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	OOCUMENT NUMBER  6,624,589  6,628,053  6,626,719  2002/0060516 A1  2002/0057045 A1  2002/0057045 A1  2003/0006684 A1  2003/0048055 A1  2003/0057860 A1  6,087,765  5,872,422  2002/009637  DOCUMENT NUMBER  WO 01/93292  10-149760	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  F REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)  U.S. F  OCCUMENT NUMBER DATE  6,624,589 9/03  6,628,053 9/03  6,626,719 9/03  2002/0060516 A1 5/02  2002/0031972 A1 3/02  2002/0057045 A1 5/02  2002/0057045 A1 5/02  2003/0006684 A1 1/03  2003/0048055 A1 3/03  2003/0057860 A1 3/03  6,087,765 7/00  5,872,422 2/16/99  2002/0009637 1/02  FOREIG  DOCUMENT NUMBER  WO 01/93292 12/01  10-149760 6/98	03500.015727.1   APPLICANT   APPLICANT   APPLICANT   FILED HERE   U.S. PATENT DOCUMENTS   DATE   NAME   C.S. PATENT DOCUMENT   NUMBER   DATE   NAME   C.S. PATENT DOCUMENT   NUMBER   DATE   NAME   C.S. PATENT DOCUMENT   DATE   NAME   C.S. PATENT DOCUMENT   DATE   NAME   C.S. PATENT DOCUMENTS   DATE   C.S. PATENT DOCUMENT   DATE   C.S. PATENT DOCUMENT   DATE   C.S. PATENT DATE   DATE   C.S. PATENT DATE   DA	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	03500.015727.1   NYA   APPLICANT   FREFERENCES CITED BY APPLICANT    FREFERENCES CITED BY APPLICANT    FREFERENCES CITED BY APPLICANT    FREFERENCES CITED BY APPLICANT    FREFERENCES CITED BY APPLICANT    TAKEO TSUKAMOTO   FILING DATE   FILED HEREWITH   GROUP   FILING DATE   FILED HEREWITH   U.S. PATENT DOCUMENTS   U.S. PATENT DOCUMENT   U.S. SUBCLASS   U.S. U.S. SUBCLASS   U.S. U.S. U.S. U.S. U.S. U.S. U.S.		

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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'EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME		CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AMH	4,728,851	3/88	Lambe		313	309	
AmH	4,904,895	2/90	Tsukamoto et al.		313	336	
AMH	5,986,389	11/99	Tsukamoto		313	309	
AMH	6,147,449	11/00	lwasaki et al.		313	495	
AmH	6,171,162	1/01	lwasaki et al.		445	6	
AMH	6,184,610	2/01	Shibata et al.		313	309	·
AmH	6,231,413	5/01	Tsukamoto		445	24	
AmH	6,246,168	6/01	Kishi et al.		313	495	
AMH	6,288,494	9/01	Tsukamoto et al.		315	169.1	
AmH	5,982,091	11/99	Konishi		313	495	
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AMH	0 614 209 A1	9/94	EPO				
AMH AMH AMH AMH	8-115652	5/96	JAPAN		<u>.</u>		ABSTRACT
AMK	7-6714	1/95	JAPAN		····		
ANH	0 290 026	11/88	EPO				ENGLISH
ANH	0 535 953 A2	4/93	ЕРО			<u></u>	ENGLISH
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ANH		C.A. Spindt et al., <i>Physical Properties of thin-Film Field Emission Cathodes with Molybdenum Cones</i> , Journal of Applied Physics, Vol. 47, No. 12 (1976) pp.5248-5263					
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'EXAMINER INITIAL	DOCUMENT NUMBER	DATE		NAME	CLASS	SUBCLASS	FILING DATE		
AMH	5,773,921	06/30/98		Keesman et al.	313	309			
AmH	5,973,444	10/26/99		Xu et al.	313	309			
AmH	5,935,639	8/10/99		Sullivan et al.	427	78			
AmH	4,956,578	9/11/90		Shimizu et al.	315	3			
Amlt	5,185,554	2/9/93		Nomura et al.	313	495			
AmH	6,448,709	9/02		Chuang et al.	313	497			
AmH	6,204,597	03/01		Xie et al.	313	310			
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AMH	WO 89/07163	08/10/89		Japan			English		
MH	WO 90/07023	06/28/90		PCT			English		
AMH	JP 08-115652	05/07/96		Japan			Abst.& Transl.		
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DWH		Catalytic Grov	wth	of Carbon Filaments," 27 (3) Carbor	315-32	3 (1989).			
AMH	S. lijima, "Helic	al Microtubul	es o	f Graphitic Carbon," Nature, Vol. 34	5, 56-58	3 (1991).			
AMH AMH	T. W. Ebbesen (1992).	et al., " Large	-Sca	lle Synthesis of Carbon Nanotubes,	" Natur	e, Vol. 358,	220-222		
AMH	W. A. DeHeer e			bon Nanotube Films: Production ar 5-847 (1995).	d Optio	al and Elec	etronic		
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AmH	5,577,943	11/96		Vickers et al.	445	24		
AmH	2002/136896	09/26/00		Takikawa et al.	428	408		
AMH	5,192,240	03/09/93	_	Komatsu	445	24		
AmH	5,214,346	05/25/93		Komatsu	313	309		
AMH	5,382,867	01/17/95		Maruo et al.	313	309		
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PmH	6,313,572	11/06/01		Yamada	313	310		
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AMH	0 758 028 A2	02/12/97		EPO	D01F	9/127	English	
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AMH	2000/277003	06/10/00		Japan	H01J	9/02	No	
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<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO 1449 (modified) ATTY DOCKET NO. APPLICATION NO. 03500.015727.1 NYA U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE APPLICANT **TAKEO TSUKAMOTO** LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) FILING DATE 2879 GROUP **FILED HEREWITH** U.S. PATENT DOCUMENTS **'EXAMINER** DOCUMENT FILING DATE NUMBER DATE SUBCLASS INITIAL NAME CLASS 10/24/00 6,135,839 lwase et al. 445 24 2002/0031972 3/02 Kitamura et al. 445 6/02 6,400,091 Deguchi et al. 169.1 315 AMH 6,420,726 7/02 Choi et al. 257 10 FOREIGN PATENT DOCUMENTS TRANSLATION DOCUMENT DATE COUNTRY SUBCLASS CLASS YES/NO/ NUMBER OR ABSTRACT AMH 0 797 233 A2 09/24/97 **EPO** H01J 1/30 **English** 0 980 089 A1 02/16/00 **EPO** H01J 1/30 **English** 0 986 084 A2 03/15/00 **EPO** H01J 1/30 **English** 1 117 118 A1 07/08/01 **EPO** H01J 1/312 English 06/12/96 **EPO** 0716439 H01J 3/02 English 1 113 478 A1 7/01 **EPO** Abst. & corresponding **JAPAN** 2-112125 04/24/90 H01J 1/30 U.S. Patent 4,956,578 OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.) BWH H. Dai et al., "Single-Wall Nanotubes Produced by Metal-Catalyzed Disproportionation of Carbon Monoxide," Chem. Phys. Lett., Vol. 260, 471-475 (1996). H. Dai et al., "Nanotubes as Nanoprobes in Scanning Probe Microscopy," Nature, Vol. 384, 147-150 (1996). A. C. Dillon et al., "Storage of Hydrogen in Single- Walled Carbon Nanotubes," Nature, Vol.386, 377-379 (1997). W.P. Dyke et al., "Field Emission", Advances in Electronics and Electron Physics, Vol. 8, (1956) pp. 89-185 C.A. Spindt et al., "Physical Properties of Thin-Film Field Emission Cathodes with Molybdenum Cones", Journal of Applied Physics, Vol. 47, No. 12 (1976), pp. 5248-5263

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part	3-20941	01/29/91		JAPAN	H01、	31/12	Abst. & corresponding U.S. Patent 5,185,554		
BUH	5-211029	08/20/93		JAPAN	H01.	1/30	No		
AMH	8-264109	10/11/96		JAPAN	H01.	1/30	Abst.		
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AMH	1 122 344 A3	8/01		EPO	<u> </u>				
AMH	A0 913 508	05/06/99		EPO	D011	9/127	English		
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AMH	A1 443 865	08/28/91		EPO	H01.	J 21/10	English		
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Why Why Why	Toshlaki Kusunoki et al., "Fluctuation-Free Electron Emission from Non-Formed Metal-Insulator-Metal (MIM) Cathodes Fabricated by Low Current Anodic Oxidation", Japanese Journal of Applied Physics, Vol. 32 No. 11B, (1993), p. L1695-1697								
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DANK	G. Dittmer, "Ele			n and Electron Emission of Discont	tinuous	Thin Films	", Thin		

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'EXAMINER INITIAL	DOCUMENT NUMBER	DATE		NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE		
	2001/0006232 A1	7/01		Choi et al.					
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Anut	04-212236	03/08/92		Japan	H01J	1/30	No		
Amt	03-295131	12/26/91		Japan	H01J	1/30	No		
AMH	A2 535 953	04/07/93		EPO	H01J	1/30	English		
Amt	05-159696	06/25/93		Japan	H01J	1/30	No		
Amtt	05-198253	08/06/93		Japan	H01J	. 1/30	No		
AMH	05-274997	10/22/93		Japan	H01J	1/30	Abst.		
Amth	11-232997	08/27/99		Japan	H01J	1/30	No		
MMH	A1 936 650	08/18/99		EPO	H01J	3/02	English		
Amtt	10-289650	10/27/98		Japan	H01J	1/30	No		
AMH	A1 871 195	10/14/98		EPO	H01J	1/30	English		
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AmH	6,472,814 B1	10/02	Yamanobe et al.	313	495	11/13/98		
Amt	5,847,495	12/98	Yamanobe et al.	313	310			
AMH	5,066,883	11/91	Yoshioka et al.	313	309			
AmH	6,455,021 B1	09/02	Saito	423	447.3	07/20/99		
AmH	6,471,936 B1	10/02	Chen et al.	423	658.2	03/02/00		
Amt	6,283,812 B1	09/01	Jin et al.	445	24	01/25/99		
Amt	4,816,289	03/89	Komatsu et al	423	447.3			
Amt	5,443,859	08/95	Nagata	427	122			
Amth	5,618,875	04/97	Baker et al.	524	495			
Amu	5,690,997	11/97	Grow	427	249			
AmH	6,129,602	10/00	Yamanobe	445	24			
Amtt	6,228,904 B1	05/01	Yadav et al.	523	210			
Amth	6,333,016 B1	12/01	Resasco et al.	423	447.3	9/3/99		
AmH	6,413,487 B1	07/02	Resasco et al.	423	447.3	6/2/00		
Amt	6,445,006 B1	09/02	Brandes et al.	257	76	7/27/99		
Amt	5,981,305	11/99	Hattori	438	20			
Amtt	6,290,564 B1	9/01	Talin et al.	445	50	9/30/99		
Ant	5,458,784	10/95	Baker et al.	210	674	5/3/00		
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Amt	6,390,612 B1	05/02		Kotaki et al.	347	85				
ANT	5,872,541	02/99		Yoshioka et al.	345	74	2.1.2.1.1.2.1.1			
Amtt	5,543,684	08/96		Kumar et al.	313	495				
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Amtt	2002/0009637 A1	1/24/02	<u>.</u>	Murakami et al	429	213	2/5/01			
Amth	2002/0047562 A1	04/25/02		Kitamura et al.	315	169.3	05/29/01			
Amt	5,770,918	6/98		Kawate et al.	313	495				
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Amit	2002/0146958 A1	10/02		Ono et al.	445	24				
Amit	2003/0048056 A1	3/03		Kitamura et al.	313	311				
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<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

## FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

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APPLICATION NO. NYA

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TAKEO TSUKAMOTO

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AMH	0 535 953 B1	01/96	EPO	H01J	1/30	English	
AMH	1 122 344 A2	08/01	EPO	D01F	9/127	English	
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<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

## FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

LIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)

ATTY	DOCKET	NO.
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03500.015727.1

APPLICATION NO. NYA

APPLICANT

TAKEO TSUKAMOTO

FILING DATE

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GROUP

2879

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	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT		
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